

# Search Notes



Application/Control No.

10/517,090

Examiner

Sam K. Ahn

Applicant(s)/Patent under Reexamination

TSATSANIS ET AL.

Art Unit

2611

## SEARCHED

Class	Subclass	Date	Examiner
375	219, 223, 257, 296, 349, 346	12/4	a
398	193		
455	114.3, 557		
700	53	12/11	a
updated search		5/16	a

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST inventor search keyword and citation search IEEE and google keyword and citation search	12/4	a
consulted Young Lee 375 P.E.	12/11	a
EAST, IEEE and google updated search	5/16	a